

PROBE CARD

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Abstract of JP2124469

PURPOSE: To make it possible to compensate for errors due to the resistance of a probe by providing a probe wherein the tips of conductors as a force line and a sensing line are connected, and the connecting part is made to be a contact point to a kelvin contact point and a material to be measured.
CONSTITUTION: A first conductor 104a comprising a gold plated steel material is covered with an insulator 104b comprising Teflon. The insulator is wrapped with a second conductor 104c. A coaxially shaped probe 104 formed in this way is attached to a board 103 with a solder 107. The tip parts of the conductors 104a and 104c are welded. Wiring conductors 106a and 106b which are connected to the other ends of the conductors 104a and 104c are connected to terminals 108a and 108b, respectively. When a connecting point 110 of the conductors 104a and 104c is made to be a kelvin contact point, measuring errors due to the resistance of the probe 104 can almost be eliminated.

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